

PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.

200207084-1

APPLICATION NO.

10/600,878

CONFIRMATION NO.

APPLICANT

John Wu et al.

FILING DATE

Herewith 6/20/03

GROUP

2827

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
HU	1A	6,256,241 B1	Jul. 3, 2001	Mehalel	
HU	1B	6,501,692 B1	Dec. 31, 2002	Melanson et al.	
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

HU	1Q	Sanjay Sengupta et al., "Defect-Based Test: A Key Enabler for Successful Migration to Structural Test," Intel Technology Journal, Q1, 1999, pp. 1-14.
	1R	
	1S	

EXAMINER

Huan Huang

DATE CONSIDERED

3/5/06